



PATENT  
Attorney's Docket No. 3521.217

ART UNIT: 2877  
EXAMINER: Hwa S. Lee

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

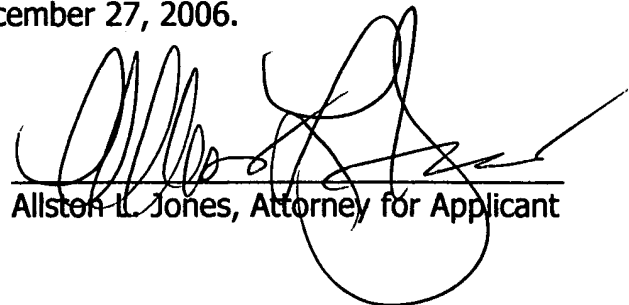
In re Application of:	)	
ARES J. ROSAKIS et. al	)	<b><u>RESPONSE TO</u></b>
	)	
Serial No.: 10/767,406	)	<b><u>EXAMINER'S ACTION AND</u></b>
	)	
Filed: January 28, 2004	)	<b><u>AMENDMENT A</u></b>
	)	
	)	

For: FULL-FIELD OPTICAL MEASUREMENTS OF SURFACE PROPERTIES OF PANELS,  
SUBSTRATES AND WAFERS

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**EXPRESS MAIL CERTIFICATE**

I hereby certify that this paper, and the listed enclosures, and fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated below and is addressed to Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 with the Express Mail Label No. EV484313718US on December 27, 2006.

  
Allston L. Jones, Attorney for Applicant

Dear Sir:

This response is being submitted to the Examiner's Action dated June 28, 2006 together with a three month time extension to extend the time for response to December 28, 2006.